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INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
Date Submitted: August 6, 2003

	Complete if Known	
Application Number	09/893,709	
Filing Dat	06/29/2001	
First Nam d Inv ntor	Lambert DANNER	
Group Art Unit	2873	
Examiner Name	S. Sugarman	
Alterney Docket Number	016790-0430	

(use as many sheets as necessary)
Sheet 1 of 3

				U.S. PATENT DOCUMENTS		
	671	U.S. Patent D	ocument	Name of Botanda and Ameliand of	Date of Publication of	Pages, Columns, Lines, Where Relevant
Examiner Initials*	Cite No. <sup>1</sup>	Number	Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document	Cited Document MM-DD-YYYY	Passages or Relevant Figures Appear
541	A1	5,978,087		PATTERSON ET AL.	11/02/1999	
48	A2	5,963,327		HE ET AL.	10/05/1999	
KIS	A3	5,877,859		ASPNES ET AL.	03/02/1999	
4/4	A4	5,349,471		MORRIS ET AL.	09/20/1994	
305	A5	5,166,752		SPANIER ET AL.	11/24/1992	
- M	A6	4,671,657		CALVANI ET AL.	06/09/1987	<u></u>
NA	A7	2002/0024669	A1	DANNER ET AL.	02/28/2002	
- 10						

				FC	REIGN PATENT DOCUMEN	rs		
Examiner Initials*	Cite No.	Office		ment nd Code <sup>5</sup> if known)	Name of Patentee or Applicant of Cited Documents	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T⁵
91	A8	JP	2002-098591	Α	LEICA MICROSYSTEMS WETZLER GMBH	04/05/2002		Abstract
913	A9	wo	99/02950	A1	OPTICAL INSIGHTS, LLC	01/21/1999		
SAU	A10	WO	96/18205	A1	MOLECULAR DYNAMICS, INC.	06/13/1996		
90	A11	wo	92/12404,	A1	RUDOLPH RESEARCH CORPORATION	07/23/1992		
441	A12	wo	91/14157	A2	BRAN + LUESBE GMBH	09/19/1991		Abstract
R. X	A13	EP	1 172 642	A2	LEICA MICROSYSTEMS WETZLER GMBH	01/06/2002		Abstract
7/3	A14	JP	7-229720	A	NIHON DENKI KK	08/29/1995		Transl.

	NON PATENT LITERATURE DOCUMENTS							
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.	Ť					
1/4	A15	Affidavit from John Woollam, President of J.A. Woollam Co., Oct. 1, 2002.						
5/1	A16	Affidavit from Hiroki Hashimoto of Fujitsu Corporation (English and Japanese language) dated 9/2/2002, along with Fujitsu Purchase Order sheet and Acceptance Report by Fujitsu of Woollam Company Achromatic focusing M-44 Ellipsometer dated 07/08/1999.						
708	A17	Affidavit from Michio Suzuki of J.A. Woollam Co., Japan (English and Japanese language) dated 9/2/2002, along with Purchase Order Sheet by Japan company from J.A. Woollam Co., Lincoln, for an achromatic focusing M-44 for Fujitsu dated 7/5/1999.						

		فتحد كالمتحدد المتحدد	
Examiner Signature	S. J. Sugarman	Date Considered	12-2003

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<sup>&</sup>lt;sup>1</sup> Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>4</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>5</sup>Applicant is to place a check mark here if English language Translation is attached.

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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(use as many sheets as necessary) 2 of 3 Sheet

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Attorney Docket Number	016790-0430					

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40	A18	Affidavit from Gen Wang of Samsung Information Systems America, Inc., dated 08/28/2002, along with the Purchase Order and Original Quotation for achromatic focusing M-44 from J.A. Woollam Co., dated 01/07/1997.	
S	A19	Affidavit from Erik Bylin, Materials Director, NANOmetrics Corporation, 09/20/2002.	
SA	A20	Multiwavelength Ellipsometers, Vintage J.A. Woollam Co., M-44/M-88, December 1996.	
M.	A21	Letter from Roger Bruhn, R. Bruhn Photography + Design, with attachment.	
5/8	A22	Multilayer Optical Spectrometer Scanner, SOPRA Brochure, March 1989, pages 2-6.	
50	A23	Yufeng Li, "Flying Height Measurement on Al <sub>2</sub> O <sub>3</sub> Film of a Magnetic Slider", Tribology, Vol. 119, October 1997, pages 681-686.	
4/	A24	J. A. Zapien et al., *Real-time Spectroscopic Ellipsometry from 1.5 to 6.5 eV*, Thin Solid Film, Vol. 364, Nos. 1,2, March 27, 2000, pages 16-21.	
SI	A24	E. Hecht, "More on Geometrical Optics", OPTICS, Chapter 6, 1977, pages 232-239.	
993	A25	M. E. El-Ghazzawi et al., "Spectroellipsometry Characterization of Directly Bonded Silicon-on-Insulator Structures", Thin Solid Films, Vol. 223, 1993, pages 218-222.	
<b>59</b> %	A26	Edmund Industrial Optics, 1999 Optics and Optical Instruments Catalog pages, 3 pages	
4)	A27	Purchase Orders from Edmund Scientific Company to J.A. Woollam Co. dated October 14, 1999, April 13, 1998 and March 28, 1996.	

Examiner Signature	S-J:Sygeman	Date Considered	12-2003

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Sheet	3	of	3	Attorney Docket Number	016790-0430	

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9)	A28	Alleged Evidence J.A. Woollam Co., sold Edmund Scientific Achromatic Lens to Fujitsu, Samsung, and Nanometrics including Bill of Materials of M44-FCS-OPTICS shipped 10/13/1999 showing EDMUND Part 32,311 Achromatic Lens 34.47 was included, 12 pages.	
A)	A29/	Alleged Representative/Example Purchase Orders and Packing Lists for sales of J.A. Woollam focused (achromatic) spectroscopic M-44 ellipsometers to NANOmetrics Corporation. Dates are prior to July 11, 2000, 6 pages.	
40	A30	Order bills for M-44 Ellipsometer with achromatic focusing lenses for NANOmetrics Corporation. Order numbers correspond with Packing List and Purchase Order Receiver numbers listed in Erik Bylin's Affidavit, 20 pages.	
SU	,A31	Purchase Orders from Melles Griot Corp. to J.A. Woollam Co., for Achromatic Lenses, 1997, 8 pages.	
5M	A32	Purchase Order No. P9508-F29, J.A. Woollam Japan Corporation, December 1, 1995, 2 pages.	
94	A33	J.A. Woollam Co., Inc., FS-110 Vertical Ellipsometer focused Beam System Upgrade Installation Instructions, 2-21-1994, pages 2-3.	
59p	A34	Advertisement for VASE, R&D Magazine, February 1999, page 38.	

Examin r Signature	S. J. Sugaman	Date Considered	12-2007
Signature	0.00	Considered	, , ,

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